



JFIV

Docket No.: S&ZIO030801

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By:

Date: June 7, 2005

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No.	:	10/653,653	Confirmation No: 3425
Applicant	:	Michael Kandler	
Filed	:	September 2, 2003	
Title	:	Sensor Module	
Art Unit	:	2855.0	
Examiner	:	Andre J. Allen	
Docket No.	:	S&ZIO030801	
Customer No.	:	24131	

INFORMATION DISCLOSURE STATEMENT  
UNDER 37 C.F.R. 1.97(C)(1)

Hon. Commissioner for Patents

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

German Patent DE 198 25 761 C2 (Hillerich et al.), dated December 16, 1999, and English abstract thereof, which discloses an apparatus for detecting the stretching and/or compression of a body. The apparatus comprises a deformable semiconductor substrate 102 on which at least one element having a physical property that changes, depending on the stretching and/or compression of the substrate 102, is arranged (see piezoresistive resistor traces 116 and 118 in Fig. 2 of DE 198 25 761 C2, for example). An evaluation device (see elements 108, 112a, 112b and 110 in Fig. 2) is arranged on the substrate and connected to the elements 116 and 118 to produce a measuring signal depending on the stretching and/or compression of a body to which the apparatus is attached. The evaluation device is arranged on the substrate so that it can be stretched and/or compressed. Switching elements of the evaluation device are arranged so that influences of stretching and/or compression on the function of the evaluation device are minimal.

According to Fig. 3 of DE 198 25 761 C2, the semiconductor substrate 102 is attached to a body 134 by an adhesive layer 136, for example. In addition, a foil 120 having an opening 122 is provided for protection. It is indicated in column 7, lines 38-41 of DE 198 25 761 C2 that, likewise, a foil 120 without an opening could be used. According to Fig. 4A of DE 198 25 761 C2, a foil 120 without an opening is used. Moreover, according to Fig. 4A, the conformable semiconductor substrate 102 is attached to a lower support foil 138.

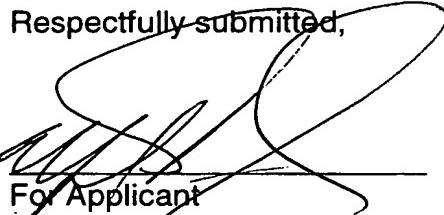
Finally, it is outlined in column 10, lines 24 to 31 that the evaluation device may include a wireless RF transceiver, a so-called transponder to integrate such a transponder with the evaluation device. In such a case, the required antenna can be integrated within the upper or lower support foil, for example.

Fig. 5 of DE 198 25 761 C2 shows a block diagram of an evaluation means comprising a memory 538.

German Examination Report dated May 2, 2005.

In accordance with 37 C.F.R. 1.97(e) the undersigned herewith states that each item of information contained in the information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement.

In accordance with 37 C.F.R. 1.97 (c) (1), consideration of this Information Disclosure Statement is requested.

Respectfully submitted,  
  
For Applicant

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Sheet 1 of 1

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Attorney Docket No.: <b>S&amp;ZIO030801</b>	Applic. No. <b>10/653,653</b>
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))		Applicant <b>Michael Kandler</b>	
		Filing Date <b>September 2, 2003</b>	Group Art Unit <b>2855</b>

### U.S. PATENT DOCUMENTS

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

### FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES   NO
	J	198 25 761 C2	12/16/99	Germany			
	K						
	L						
	M						
	N						

### OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	O	
	P	

EXAMINER	DATE CONSIDERED
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	